

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2814

Examiner: Quach, Tuan N.

In re Application of

Kuniko Kikuta

Serial No.: 09/584,739

Filed: June 1, 2000

For: COPPER-ALLOY INTERCONNECTION LAYER

Honorable Commissioner of Patents Washington, D.C. 20231

BOX AF

AMENDMENT UNDER 37 C.F.R. §1.116

Sir:

In response to the Office Action dated July 2, 2002, please amend the above-

identified application as follows:

IN THE CLAIMS:

Please amend the following claims:

1. (Amended) An electrically conductive layer comprising:

a copper allow which includes at least one of Bi, Sb, and Ti at not less than 0.1 percent

by weight,

wherein said copper alloy has a melting point less than copper.

22. Amended) A semiconductor device comprising:

a semiconductor substrate;

an insulation layer over said semiconductor substrate, and said insulation layer having

a trench groove;

a barrier metal layer on a bottom and side walls of said trench groove; and